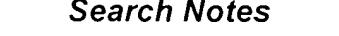


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/706,084	NAKAO ET AL.
	Examiner Huan H. Tran	Art Unit 2861

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner